## In the Title:

Amend the title as follows:

<u>Low Power Testing Of Very Large Circuits</u> <u>IC With Separate</u> <u>Scan Paths And Shift States</u>

## In the Specification:

Before paragraph [0001], insert:

This application is a divisional of prior application 10/336,985, filed January 6, 2003, now US 6,694,467, which was a divisional of prior application 09/339,734, filed June 24, 1999, now US 6,519,729, which claimed priority from prior provisional application 60/090,935, filed June 27, 1998.